Refine Search

Search Results -

Terms	Documents
L6 and (remot$3 near location)	7

Database:
US Pre-Grant Publication Full-Text Database
US Patents Full-Text Database
US OCR Full-Text Database
EPO Abstracts Database
JPO Abstracts Database
Derwent World Patents Index
IBM Technical Disclosure Bulletins
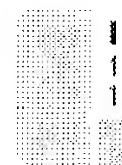
Search: L8

Refine Search

Recall Text   Clear   Interrupt

Search History

DATE: Friday, September 03, 2004   Printable Copy   Create Case

Set Name side by side	Query	Hit Count	Set Name result set
DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=OR			
L8	L6 and (remot$3 near location)	7	L8
L7	L6 and remot$3	14	L7
L6	((creat$3 or generat$3) same (categoriz$3 or categoris$3) same classificat$4 same profile) and transmit$4	22	L6
L5	((creat$3 or generat$3) same (categoriz$3 or categoris$3) same classificat$4 same profile) and transmit$	22	L5
L4	((creat$3 or generat$3) same (categoriz$3 or categoris$3) same classificat$4 same profile) and access$3	25	L4
L3	(creat$3 or generat$3) same (categoriz$3 or categoris$3) same classificat$4 same profile same schema	4	L3
L2	(creat$3 or generat$3) same (categoriz$3 or categoris$3) same classificat$4 same profile same (data near element)	0	L2
L1	(creat$3 or generat$3) same (categoriz$3 or categoris$3) same classificat$4 same profile same element	4	L1

END OF SEARCH HISTORY

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE

◆IEEE

Membership   Publications/Services   Standards   Conferences   Careers/Jobs

IEEE Xplore
RELEASE 1.3

Welcome
United States Patent and Trademark Office

II
1
1

Help   FAQ   Terms   IEEE Peer Review

Quick Links ▼

» Sea

Welcome to IEEE Xplore

○ Home
○ What Can I Access?
○ Log-out

Tables of Contents

○ Journals & Magazines
○ Conference Proceedings
○ Standards

Search

○ By Author
○ Basic
○ Advanced

Member Services

○ Join IEEE
○ Establish IEEE Web Account
○ Access the IEEE Member Digital Library

IEEE Enterprise

○ Access the IEEE Enterprise File Cabinet

Your search matched **0** of **1067317** documents.
A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

Refine This Search:
You may refine your search by editing the current search expression or enteri new one in the text box.
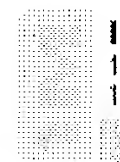
| categor* <paragraph> schema <paragraph> profile | Search

☐ Check to search within this result set

Results Key:
JNL = Journal or Magazine   **CNF** = Conference   **STD** = Standard

Results:
No documents matched your query.

🖳 Print Format

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search | Join IEEE | Web Account |
New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting | No Robots Please | Release Notes | IEEE Online
Publications | Help | FAQ| Terms | Back to Top

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE

◆IEEE

Membership   Publications/Services   Standards   Conferences   Careers/Jobs

IEEE *Xplore* RELEASE 1.8

Welcome
United States Patent and Trademark Office

» Sea

Help   FAQ   Terms   IEEE Peer Review

Quick Links ▾

Welcome to IEEE Xplore~

- ○ Home
- ○ What Can I Access?
- ○ Log-out

Tables of Contents

- ○ Journals & Magazines
- ○ Conference Proceedings
- ○ Standards

Search

- ○ By Author
- ○ Basic
- ○ Advanced

Member Services

- ○ Join IEEE
- ○ Establish IEEE Web Account
- ○ Access the IEEE Member Digital Library

IEEE Enterprise
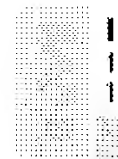
- ○ Access the IEEE Enterprise File Cabinet

Your search matched **0** of **1067317** documents.
A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

Refine This Search:
You may refine your search by editing the current search expression or enteri
new one in the text box.

(creat* <or> generat*) <paragraph> categoriz* <para   [Search]

☐ Check to search within this result set

Results Key:
JNL = Journal or Magazine   **CNF** = Conference   **STD** = Standard

Results:
No documents matched your query.

🖶 Print Format

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search | Join IEEE | Web Account |
New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting | No Robots Please | Release Notes | IEEE Online
Publications | Help | FAQ| Terms | Back to Top

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE

◆IEEE

Membership   Publications/Services   Standards   Conferences   Careers/Jobs

IEEE Xplore
RELEASE 1.8

Welcome
United States Patent and Trademark Office

Help   FAQ   Terms   IEEE Peer Review

Quick Links ▼

» Sea

Welcome to IEEE Xplore

○ Home
○ What Can
   I Access?
○ Log-out

Tables of Contents

○ Journals
   & Magazines
○ Conference
   Proceedings
○ Standards

Search

○ By Author
○ Basic
○ Advanced

Member Services

○ Join IEEE
○ Establish IEEE
   Web Account
○ Access the
   IEEE Member
   Digital Library

IEEE Enterprise

○ Access the
   IEEE Enterprise
   File Cabinet

Your search matched **0** of **1067317** documents.
A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

Refine This Search:
You may refine your search by editing the current search expression or enteri new one in the text box.

(categor* <or> classif* <or> group*) <paragraph> sch | Search |

☐ Check to search within this result set

Results Key:
JNL = Journal or Magazine   **CNF** = Conference   **STD** = Standard

Results:
No documents matched your query.

🖶 Print Format

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search | Join IEEE | Web Account |
New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting | No Robots Please | Release Notes | IEEE Online
Publications | Help | FAQ| Terms | Back to Top

IEEE *Xplore* RELEASE 1.8

Welcome
United States Patent and Trademark Office

» Sea

Help   FAQ   Terms   IEEE Peer Review   **Quick Links** ▼

Home
What Can I Access?
Log-out

Tables of Contents
Journals & Magazines
Conference Proceedings
Standards

Search
By Author
Basic
Advanced

Member Services
Join IEEE
Establish IEEE Web Account
Access the IEEE Member Digital Library

IEEE Enterprise
Access the IEEE Enterprise File Cabinet

🖶 Print Format

Your search matched **4** of **1067317** documents.
A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

Refine This Search:
You may refine your search by editing the current search expression or enteri
new one in the text box.

|(((creat* <or> generat*) <paragraph> classif* <paragr   [Search]

☐ Check to search within this result set

Results Key:
JNL = Journal or Magazine   **CNF** = Conference   **STD** = Standard

---

1 **Diagnostics of bar and end-ring connector breakage faults in polyph induction motors through a novel dual track of time-series data minin and time-stepping coupled FE-state space modeling**
Povinelli, R.J.; Bangura, J.F.; Demerdash, N.A.O.; Brown, R.H.;
Energy Conversion, IEEE Transactions on , Volume: 17 , Issue: 1 , March 200
Pages:39 - 46

[Abstract]   [PDF Full-Text (196 KB)]   **IEEE JNL**

---

2 **Diagnostics of eccentricities and bar/end-ring connector breakages polyphase induction motors through a combination of time-series data mining and time-stepping coupled FE-state-space techniques**
Bangura, J.F.; Povinelli, R.J.; Demerdash, N.A.O.; Brown, R.H.;
Industry Applications, IEEE Transactions on , Volume: 39 , Issue: 4 , July-Aug 2003
Pages:1005 - 1013

[Abstract]   [PDF Full-Text (609 KB)]   **IEEE JNL**

---

3 **Morphological profiles used for classification of data from urban are**
Benediktsson, J.A.; Arnason, K.; Pesaresi, M.;
Geoscience and Remote Sensing Symposium, 2002. IGARSS '02. 2002 IEEE
International , Volume: 1 , 24-28 June 2002
Pages:305 vol.1

[Abstract]   [PDF Full-Text (218 KB)]   **IEEE CNF**

---

4 **Integrated multimedia processing for topic segmentation and classification**
Jasinschi, R.S.; Dimitrova, N.; McGee, T.; Agnihotri, L.; Zimmerman, J.; Li, D

Image Processing, 2001. Proceedings. 2001 International Conference on , Vol
3 , 7-10 Oct. 2001
Pages:366 - 369 vol.3

[Abstract]   [PDF Full-Text (432 KB)]   **IEEE CNF**

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search | Join IEEE | Web Account |
New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting | No Robots Please | Release Notes | IEEE Online
Publications | Help | FAQ| Terms | Back to Top